## Notice of References Cited Application/Control No. 10/581,523 Examiner DEREK S. CHAPEL Applicant(s)/Patent Under Reexamination SEKIGUCHI ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

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*	Α	US-6,519,016	02-2003	Ichihashi et al.	349/117
	В	US-			
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	D	US-			
	Е	US-			
	F	US-			
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## **NON-PATENT DOCUMENTS**

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